

# **DATA SHEET**

# SURFACE MOUNT MULTILAYER <u>CERAMIC CAPACITORS</u>

Automotive grade High Temperature Application X8G / X8R

I nF to 100 nF

RoHS compliant & Halogen Free



YAGEO





**YAGEO** 

This specification describes Automotive grade X8G / X8R series chip capacitors with leadfree terminations and used for automotive equipments.

#### <u>APPLICATIONS</u>

Decoupling, smoothing, snubber and resonant of high temperature operating equipment.

#### **FEATURES**

- · AEC-Q200 qualified
- Operating temperature range: -55 to 150°C
- MSL class: MSL I
- · Soldering is compliant with J-STD-020D
- Halogen free epoxy
- RoHS compliant
- · Reduce environmentally hazardous waste
- High component and equipment reliability
- The capacitors are 100% performed by automatic optical inspection prior to taping.

#### ORDERING INFORMATION - GLOBAL PART NUMBER

All part numbers are identified by the series, size, tolerance, TC material, packing style, voltage, process code, termination and capacitance value.

#### **GLOBAL PART NUMBER**

AC xxxx x x xxx x B x xxx

(1) (2) (3) (4) (5) (6) (7)

#### (I) SIZE – INCH BASED (METRIC)

0805 (2012)

#### (2) TOLERANCE

 $F = \pm 1\%$ 

 $G = \pm 2\%$ 

 $| = \pm 5\%$ 

 $K = \pm 10\%$ 

 $M = \pm 20\%$ 

#### (3) PACKING STYLE (SEE TABLE 3)

R = Paper/PE taping reel; Reel 7 inch

K = Blister taping reel; Reel 7 inch

P = Paper/PE taping reel; Reel 13 inch

F = Blister taping reel; Reel 13 inch

#### (4) TC MATERIAL

X8G: 0±30 ppm/°C

X8R: ±15%

#### (5) RATED VOLTAGE

7 = 16 V

8 = 25 V

9 = 50 V

0 = 100 V

#### (6) PROCESS

N = Class I MLCC (X8G)

B = Class II MLCC (X8R)

#### (7) CAPACITANCE VALUE

2 significant digits+number of zeros

The 3rd digit signifies the multiplying factor, and letter R is decimal point

Example:  $121 = 12 \times 10^{1} = 120 \text{ pF}$ 

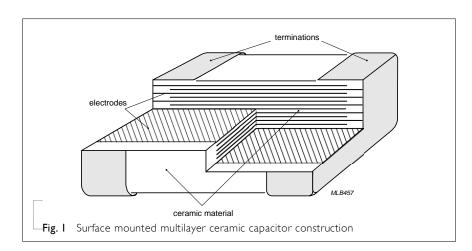




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The capacitor consists of a rectangular block of ceramic dielectric in which a number of interleaved metal electrodes are contained. This structure gives rise to a high capacitance per unit volume.

The inner electrodes are connected to the two end terminations and finally covered with a layer of plated tin (Matte Sn). The terminations are leadfree. A cross section of the structure is shown in Fig.I.



#### **DIMENSION**

**Table I** For outlines see fig. 2

		0				
TYPE	l (mm)	W (mm)	T (MM)	L <sub>2</sub> /	' L <sub>3</sub> (mm)	L <sub>4</sub> (mm)
IIFE	L <sub>I</sub> (mm)	<b>**</b> (111111)	1 (1.11.1)	min.	max.	min.
	2.0 ±0.10	1.25 ±0.10	0.60 ±0.10			
0805	2.0 ±0.10	1.25 ±0.10	0.85 ±0.10	0.25	0.75	0.70
	2.0 ±0.20	1.25 ±0.20	1.25 ±0.20			

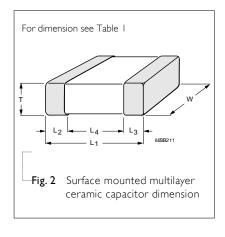
#### CAPACITANCE RANGE & THICKNESS FOR X8G

<b>Table 2-1</b> Size 0805		
CAP.	0805	
	50 V	100 V
l nF	0.6±0.1	0.6±0.1
I.2 nF	0.6±0.1	0.6±0.1
I.5 nF	0.6±0.1	0.6±0.1
I.8 nF	0.6±0.1	0.6±0.1
2.7 nF	0.6±0.1	0.6±0.1
3.3 nF	0.6±0.1	0.6±0.1
3.9 nF	0.6±0.1	0.6±0.1
4.7 nF	0.6±0.1	0.6±0.1
5.6 nF	0.6±0.1	0.6±0.1
6.8 nF	0.85±0.1	0.85±0.1
8.2 nF	0.85±0.1	0.85±0.1
I0 nF	0.85±0.1	0.85±0.1

#### NOTE

- 1. Values in shaded cells indicate thickness class in mm
- 2. Capacitance value of non E-12 series is on request

## **OUTLINES**





## CAPACITANCE RANGE & THICKNESS FOR X8R

**Table 2-2** Size 0805 0805 CAP. 16 V

	16 V	25 V	50 V
22 nF	1.25±0.2	1.25±0.2	1.25±0.2
33 nF	1.25±0.2	1.25±0.2	1.25±0.2
47 nF	1.25±0.2	1.25±0.2	1.25±0.2
68 nF	1.25±0.2	1.25±0.2	1.25±0.2
100 nF	1.25±0.2	1.25±0.2	1.25±0.2

#### NOTE

- 1. Values in shaded cells indicate thickness class in mm
- 2. Capacitance value of non E-6 series is on request

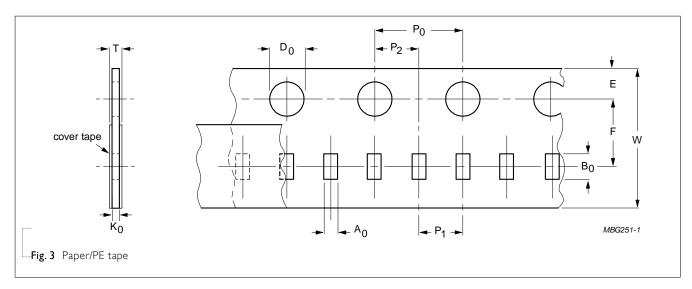
#### THICKNESS CLASSES AND PACKING QUANTITY

#### Table 3

Table 3								
		DA CV	ING CODE		QUANTITY PER REEL			
	SIZE THICKNESS CODE CLASSIFICATION	PACK	IING CODE					/ 13 INCH
CODE	CEASSITICATION	7 INCH	13 INCH		Paper	Blister	Paper	Blister
	0.60 ±0.1 mm	R	Р	8 mm	4,000		20,000	
0805	0.85 ±0.1 mm	R	Р	8 mm	4,000		15,000	
	1.25 ±0.2 mm	K	F	8 mm		3,000		10,000



#### **PAPER/PE TAPE SPECIFICATION**



**Table 4** Dimensions of paper/PE tape for relevant chip size; see Fig.3

SIZE	SYMBO	L									Unit: mm		
CODE	$A_0$	B <sub>0</sub>	W	E	F	$P_0^{(l)}$	P <sub>I</sub>	P <sub>2</sub>	$ØD_0$	K <sub>0</sub>	Т		
0201	0.39 ± 0.06	0.70 ± 0.06	8.0 ± 0.20	1.75 ± 0.1	3.50 ± 0.05	4.0 ± 0.05	2.0 ± 0.05	2.0 ± 0.05	1.55 ± 0.03	0.38 ± 0.05	(0.47 / 0.55)±0.10		
0402	0.70 ± 0.15	1.21 ± 0.12	8.0 ± 0.20	1.75 ± 0.1	3.50 ± 0.05	4.0 ± 0.05	2.0 ± 0.05	2.0 ± 0.05	1.50 +0.1 /-0	(0.75 / 0.60)±0.10	(0.85 / 0.70)±0.10		
0603	1.05 ± 0.14	1.86 ± 0.13	8.0 ± 0.20	1.75 ± 0.1	3.50 ± 0.05	4.0 ± 0.10	4.0 ± 0.10	2.0 ± 0.05	1.50 +0.1 /-0	(1.05 / 0.95 / 0.75)±0.10	(1.15 / 1.05 / 0.85)±0.10		
0805	1.50 ± 0.15	2.26 ± 0.20	8.0 ± 0.20	1.75 ± 0.1	3.50 ± 0.05	4.0 ± 0.10	4.0 ± 0.10	2.0 ± 0.05	1.50 +0.1 /-0	(1.05 / 0.95 / 0.75)±0.10	(1.15 / 1.05 / 0.85)±0.10		
1206	1.90 ± 0.15	3.50 ± 0.20	8.0 ± 0.20	1.75 ± 0.1	3.50 ± 0.05	4.0 ± 0.10	4.0 ± 0.10	2.0 ± 0.05	1.50 +0.1 /-0	(0.95 / 0.75)±0.10	(1.05 / 0.85)± 0.10		

#### NOTE

1.  $P_0$  pitch tolerance over any 10 pitches is  $\pm 0.2$  mm

#### **BLISTER TAPE SPECIFICATION**

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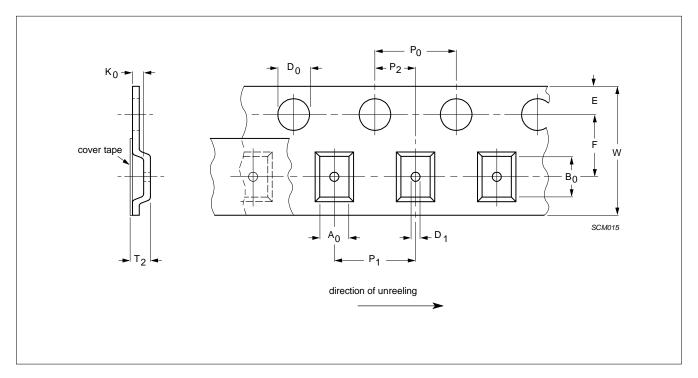


Table 5 Dimensions of blister tape for relevant chip size; see Fig.4

	SYM	IBOL													Un	it: mm
SIZE CODE	$A_0$		B <sub>0</sub>		K <sub>0</sub>		W	E	F	$ØD_0$	ØD <sub>I</sub>	P <sub>0</sub> (2)	P <sub>I</sub>	P <sub>2</sub>	T2	
	Min.	Max.	Min.	Max.	Min.	Max.					Min.				Min.	Max.
0805	1.29	1.65	2.09	2.60	1.25	1.62	8.I ±0.20	1.75 ±0.1	3.5 ±0.05	1.5 +0.1/-0.0	+0.1/-0.0	4.0 ±0.10	4.0 ±0.10	2.0 ±0.05	1.30	1.67
1206	1.65	2.12	3.30	3.75	1.22	2.15	8.I ±0.20	1.75 ±0.1	3.5 ±0.05	1.5 +0.1/-0.0	+0.1/-0.0	4.0 ±0.10	4.0 ±0.10	2.0 ±0.05	1.27	2.20
1210	2.55	3.02	3.31	3.88	0.97	2.92	8.I ±0.20	1.75 ±0.1	3.5 ±0.05	1.5 +0.1/-0.0	1 +0.1/-0.0	4.0 ±0.10	4.0 ±0.10	2.0 ±0.05	1.02	2.97
1808	2.05	2.55	4.80	5.45	1.30	2.45	12.1 ±0.20	1.75 ±0.1	5.5 ±0.05	1.5 +0.1/-0.0	1.5 +0.1/-0.0	4.0 ±0.10	4.0 ±0.10	2.0 ±0.05	1.35	2.50
1812	3.35	3.75	4.70	5.33	0.70	2.40	12.1 ±0.20	1.75 ±0.1	5.5 ±0.05	1.5 +0.1/-0.0	1.5 +0.1/-0.0	4.0 ±0.10	8.0 ±0.10	2.0 ±0.05	0.75	2.45

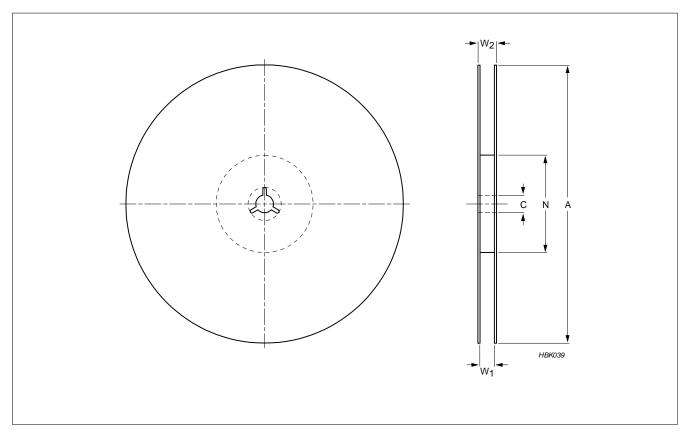
#### NOTE

- 1. Typical capacitor displacement in pocket
- 2.  $P_0$  pitch tolerance over any 10 pitches is  $\pm 0.2 \ mm$



#### **REEL SPECIFICATION**

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**Table 6** Reel dimensions; see Fig.5

TAPE WIDTH	SYMBOL				Unit: mm
	A	N	С	Wı	W <sub>2max</sub> .
8 (Ø178 mm/7")	178 ±1.0	60 ±1.0	13 +0.50/-0.20	9.4 ±1.5	14.4
8 (Ø330 mm/13")	330 ±1.0	100 ±1.0	13 +0.50/-0.20	9.0 ±0.2	14.4
12 (Ø178 mm/7")	178 ±1.0	60 ±1.0	13 +0.50/-0.20	13.4 ±1.5	18.4

#### **PROPERTIES OF REEL**

Material: polystyrene

Surface resistance:  $<10^{10}$  X/sq.





#### X8G / X8R DIELECTRIC CAPACITORS; NI/SIN TERMINATIONS

Unless otherwise specified, all test and measurements shall be made under standard atmospheric conditions for testing as given in 5.3 of IEC 60068-1:

Temperature: 15 °C to 35 °C
Relative humidity: 25% to 75%
Air pressure: 86 kPa to 106 kPa

**ELECTRICAL CHARACTERISTICS** 

Before the measurements are made, the capacitor shall be stored at the measuring temperature for a time sufficient to allow the entire capacitor to reach this temperature.

The period as prescribed for recovery at the end of a test is normally sufficient for this purpose.

Table 7 DESCRIPTION		VALUE
Capacitance range		I nF to 100 nF
Capacitance tolerance		
X8G		±1%, ±2%, ±5%
X8R	±5	% <sup>( )</sup> , ±10%, ±20%
Dissipation factor (D.F.)		
X8G	0805	
50V	I nF to 10 nF	≤ 0.1%
100V	I nF to 10 nF	≤0.1%
X8R	0805	
16V	22 nF to 100 nF	≤ 2.5%
25V	22 nF to 100 nF	≤ 2.5%
50V	22 nF to 100 nF	≤ 2.5%
Insulation resistance after 1 minute at $U_r$ (DC)	IR $\geq$ 10 G $\Omega$ or I.R $\times$ C $\geq$ 500 seconds	whichever is less
Maximum capacitance change as a function of temper (temperature characteristic/coefficient):	ature	
X8G		±30 ppm/°C
X8R		±15%
Operating temperature range:		
X8G / X8R	-	-55 °C to +150 °C

#### NOTE

I. Capacitance tolerance ±5% doesn't available for X8R full product range, please contact local sales force before order





#### **SOLDERING RECOMMENDATION**

 Tab	le	8

SOLDERING METHOD	SIZE 0402	0603	0805	1206	≥ 1210
Reflow	≥ 0.1 µF	≥ 1.0 µF	≥ 2.2 µF	≥ 4.7 µF	Reflow only
Reflow/Wave	< 0.1 µF	< 1.0 µF	< 2.2 µF	< 4.7 µF	

#### **SOLDERING CONDITIONS**

The lead free MLCCs are able to stand the reflow soldering conditions as below:

- Temperature: above 220 °C
- Endurance: 95 to 120 seconds
- Cycles: 3 times

The test of "soldering heat resistance" is carried out in accordance with the schedule of "MIL-STD-202F-method 210F", "The robust construction of chip capacitors allows them to be completely immersed in a solder bath of 270 °C for 10 seconds". Therefore, it is possible to mount MLCCs on one side of a PCB and other discrete components on the reverse (mixed PCBs). Surface Mount Capacitors are tested for solderability at 245 °C during 2 seconds. The test condition for no leaching is 260°C for 30 seconds.

### TESTS AND REQUIREMENTS

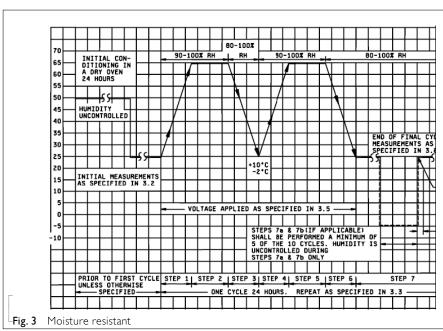
**Table 9** Test procedures and requirements

TEST	TEST METHOD		PROCEDURE	REQUIREMENTS		
Mounting	IEC 60384- 21/22	4.3	The capacitors may be mounted on printed-circuit boards or ceramic substrates	No visible damage		
Capacitance	IEC 60384- 21/22	4.5.1	X8G: At 20 °C, 24 hours after annealing $f = 1$ MHz for $C \le InF$ , measuring at voltage $I \lor_{rms}$ at 20 °C $f = 1$ KHz for $C > InF$ , measuring at voltage $I \lor_{rms}$ at 20 °C X8R At 20 °C, 24 hours after annealing $f = 1$ KHz, measuring at voltage $I \lor_{rms}$ at 20 °C	Within specified tolerance		
Dissipation Factor (D.F.)	IEC 60384- 21/22	4.5.2	X8G: At 20 °C, 24 hours after annealing $f = I$ MHz for $C \le I$ nF, measuring at voltage $I$ V <sub>rms</sub> at 20 °C $f = I$ KHz for $C > I$ nF, measuring at voltage $I$ V <sub>rms</sub> at 20 °C X8R: At 20 °C, 24 hours after annealing $f = I$ KHz, measuring at voltage $I$ V <sub>rms</sub> at 20 °C	In accordance with specification on Table 7		
Insulation Resistance	IEC 60384- 21/22	4.5.3	At U <sub>r</sub> (DC) for I minute	In accordance with specification on Table 7		





TEST	TEST METH	HOD	PROCEDURE	REQUIREMENTS	
High Temperature Exposure	AEC-Q200 3 Unpowered; 1000hours @ T=150°C  Measurement at 24±2 hours after test conclusion.		-	No visual damage ΔC/C: X8G: within ±0.5% or 0.5 pF whichever is greater X8R: ±10% D.F.: within initial specified value IR: within initial specified value	
Temperature Cycling			No visual damage  \( \Delta C/C \)  X8G: Within ±1% or 0.5pF, whichever is greater.  X8R: ±10%  D.F. meet initial specified value IR meet initial specified value		
Destructive Physical Analysis	AEC-Q200	5	Only applies to SMD ceramics. Electrical test not required.	Trineet illida specified value	
Moisture Resistance	AEC-Q200	6	T=24 hrs/per cycle; 10 continuous cycles unpowered.  Measurement at 24 ±2 hours after test condition.	No visual damage  ΔC/C  X8G: Within ±3% or 3 pF, whichever is greater	



X8R: ±15%

#### D.F.

Within initial specified value

 $X8G: \ge 10,000 \text{ M}\Omega$ 

X8R: Meet initial specified

value





TEST	TEST METHOD		PROCEDURE	REQUIREMENTS	
Biased Humidity	AEC-Q200	7	<ol> <li>Preconditioning, class 2 only:</li> <li>150 +0/-10 °C /I hour, then keep for</li> <li>24 ±1 hour at room temp</li> </ol>	No visual damage after recovery	
			<ol> <li>Initial measure:         Parameter: IR         Measuring voltage: I.5V ± 0.1 VDC         Note: Series with 100 KΩ     </li> <li>Test condition:         85 °C, 85% R.H. connected with 100 KΩ resistor, applied I.5V/U<sub>r</sub> for I,000 hours.</li> <li>Recovery:         X8G: 6 to 24 hours         X8R: 24 ±2 hours</li> <li>Final measure: IR</li> </ol>	Class 2: - Connected to 100 K $\Omega$ : $C \le 25$ nF: 1.R $\ge 4,000$ M $\Omega$ or $C > 25$ nF: (1.R-100 K $\Omega$ ) $\times$ C $\ge 100$ s. nF: Final measurement: The insulation resistance shall be greater than 10% of initial spec.	
Operational Life	AEC-Q200	NEC-Q200 8	I. Preconditioning, class 2 only: 150 +0/-10 °C /I hour, then keep for 24 ±1 hour at room temp	No visual damage  ΔC/C	
			<ul><li>2. Initial measure:</li><li>Spec: refer to initial spec C, D, IR</li><li>3. Endurance test:</li></ul>	X8G: Within ±2% or 1 pF, whichever is greater X8R: ±15%	
			Temperature: X8R: 150 °C  Specified stress voltage applied for 1,000 hours:  Applied 2.0 × Ur for ≤ 100V series  Applied 1.5 × Ur for 200V, 250V series  Applied 1.3 × Ur for 500V, 630V series  Applied 1.2 × Ur for 1 KV, 2 KV, 3 KV series	D.F. ×8G: ≤ 0.2% ×8R: within initial specified value	
			<ul><li>4. Recovery time: 24 ±2 hours</li><li>5. Final measure: C, D, IR</li></ul>	IR $\times 8G$ : $\geq 4,000 \text{ M}\Omega$ or I.R. $\times$ Cr $\geq 40\Omega$ .F whichever is less	
			Note: If the capacitance value is less than the minimum value permitted, then after the other measurements have been made the capacitor shall be preconditioned according to "IEC 60384 4.1" and then the requirement shall be met.	$\times 8R$ : $\geq 1,000  \text{M}\Omega$ or I.R. $\times$ Cr $\geq 50\Omega$ .F whichever is less	
External Visual	AEC-Q200	9	Any applicable method using × 10 magnification	In accordance with specification	
Physical Dimension	AEC-Q200	10	Verify physical dimensions to the applicable device specification.	In accordance with specification	





TEST	TEST METHOD		PROCEDURE	REQUIREMENTS
Mechanical Shock	AEC-Q200	13	Three shocks in each direction shall be applied along the three mutually perpendicular axes of the test specimen (18 shocks)  Peak value: 1,500 g's  Duration: 0.5 ms  Velocity change: 15.4 ft/s  Waveform: Half-sin	ΔC/C  X8G: Within ±0.5% or 0.5 pF, whichever is greater  X8R: ±10%  D.F.  Within initial specified value  IR  Within initial specified value
Vibration	AEC-Q200	14	5 g's for 20 minutes, 12 cycles each of 3 orientations.  Note:  Use 8" × 5" PCB. 0.31" thick 7 secure points on one long side and 2 secure points at corners of opposite sides. Parts mounted within 2" from any secure point. Test from 10-2000 Hz.	ΔC/C X8G: Within ±0.5% or 0.5 pF, whichever is greater X8R: ±10%  D.F: meet initial specified value IR meet initial specified value
Resistance to Soldering Heat	AEC-Q200	15	Precondition: $150 \pm 0/-10$ °C for I hour, then keep for $24 \pm 1$ hours at room temperature  Preheating: for size $\leq 1206$ : $120$ °C to $150$ °C for I minute  Preheating: for size $\geq 1206$ : $100$ °C to $120$ °C for I minute and $170$ °C to $200$ °C for I minute  Solder bath temperature: $260 \pm 5$ °C  Dipping time: $10 \pm 0.5$ seconds  Recovery time: $24 \pm 2$ hours	Dissolution of the end face plating shall not exceed 25% of the length of the edge concerned  \( \Delta C/C \)  X8G: Within \( \pm 1\)% or 0.5 pF, whichever is greater  X8R: \( \pm 10\)%  D.F. within initial specified value  IR within initial specified value
Thermal Shock	AEC-Q200	16	<ol> <li>Preconditioning, class 2 only:         <ul> <li>150 +0/-10 °C /I hour, then keep for 24 ± I hour at room temp</li> </ul> </li> <li>Initial measure:         <ul> <li>Spec: refer to initial spec C, D, IR</li> </ul> </li> <li>Rapid change of temperature test:         <ul> <li>X8G / X8R: -55 °C to +150 °C; 300 cycles</li> <li>I5 minutes at lower category temperature; I5 minutes at upper category temperature.</li> </ul> </li> <li>Recovery time:         <ul> <li>X8G: 6 to 24 hours</li> <li>X8R: 24 ± 2 hours</li> </ul> </li> <li>Final measure: C, D, IR</li> </ol>	No visual damage  ΔC/C  X8G: Within ±1% or 1 pF, whichever is greater  X8R: ±15%  D.F: meet initial specified value  IR meet initial specified value



**ESD** 

#### Surface-Mount Ceramic Multilayer Capacitors | Automotive grade | X8G / X8R | 16 V to 100 V

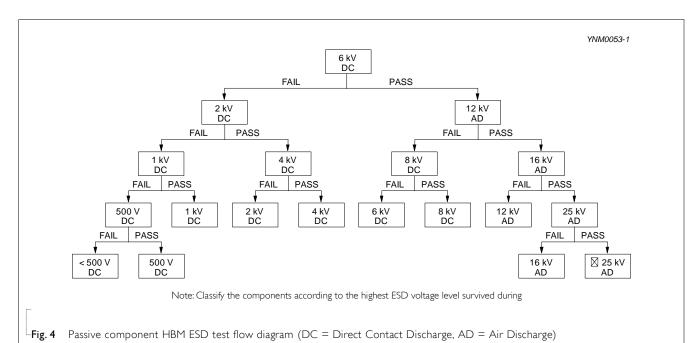
**TEST TEST METHOD** 

AEC-Q200

**PROCEDURE** Per AEC-Q200-002

#### **REQUIREMENTS**

A component passes a voltage level if all components stressed at that voltage level pass.



#### Solderability

AEC-Q200

Preheated to a temperature of 80 °C to 140 °C and maintained 18 for 30 seconds to 60 seconds.

Test conditions for lead containing solder alloy

Temperature: 235 ±5 °C Dipping time: 2 ±0.2 seconds Depth of immersion: 10 mm Alloy Composition: 60/40 Sn/Pb Number of immersions: I

Test conditions for lead-free containing solder alloy

Temperature: 245 ±5 °C Dipping time: 3 ±0.3 seconds Depth of immersion: 10 mm Alloy Composition: SAC305 Number of immersions: I

The solder should cover over 95% of the critical area of each termination.

#### Electrical Characterization

AEC-Q200

Parametrically test per lot and sample size requirements, summary to show Min, Max, Mean and Standard deviation at room as well as Min and Max operating temperatures.

 $\times 8G / \times 8R: -55$  °C to +150 °C Normal temperature: 20 °C

 $\Delta$ C/C

X8G: ±30 ppm/°C

X8R: ±15%



#### **TEST Board Flex**

**YAGEO** 

#### **TEST METHOD**

AEC-Q200

#### **PROCEDURE**

Part mounted on a 100 mm X 40 mm FR4 PCB board, which is 1.6  $\pm 0.2$  mm thick and has a layer-thickness 35  $\mu m$   $\pm$  10  $\mu m$ Part should be mounted using the following soldering reflow profile.

Conditions:

Class I:

Bending 3 mm at a rate of 1 mm/s, radius jig 340 mm

Bending 2 mm at a rate of 1 mm/s, radius jig 340 mm

#### **REQUIREMENTS**

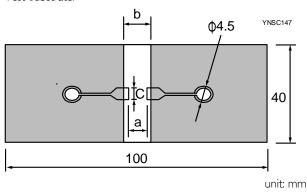
No visible damage

 $\Delta$ C/C

X8G: Within  $\pm 1\%$  or 0.5 pF, whichever is greater

X8R: ±10%

#### Test Substrate:



	Dimension(mm)		
Туре	а	b	С
0201	0.3	0.9	0.3
0402	0.4	1.5	0.5
0603	1.0	3.0	1.2
0805	1.2	4.0	1.65
1206	2.2	5.0	1.65
1210	2.2	5.0	2.0
1808	3.5	7.0	3.7

#### **Terminal** Strength

AEC-Q200

22

With the component mounted on a PCB obtained with the device to be tested, apply a 17.7N (1.8Kg) force to the side of a device being tested.

This force shall be applied for 60+1 seconds.

Also the force shall be applied gradually as not to apply a shock to the component being tested.

\* Apply 2N force for 0402 size.

Magnification of 20X or greater may be employed for inspection of the mechanical integrity of the device body, terminals and body/terminal junction. Before, during and after the test, the device shall comply with all electrical requirements stated in

#### Beam Load Test

AEC-Q200 23

Place the part in the beam load fixture. Apply a force until the part breaks or the minimum acceptable force level required in the user specification(s) is attained.

≤ 0805

this specification.

Thickness > 0.5mm: 20N Thickness ≤ 0.5mm: 8N

≥ 1206

Thickness ≥1.25 mm: 54N Thickness < 1.25 mm: 15N



Product specification  $\frac{15}{17}$ 

TEST	TEST METHOD	PROCEDURE	REQUIREMENTS
Voltage Proof		I. Specified stress voltage applied for I~5 seconds	No breakdown or flashover
		2. Ur ≤ 100 V: series applied 2.5 Ur	
		3. 100 V < Ur ≤ 200 V series applied (1.5 Ur + 100)	
		4. 200 V < Ur ≤ 500 V series applied (1.3 Ur + 100)	
		5. Ur > 500 V: 1.3 Ur	
		6. Ur≥ 1000 V: 1.2 Ur	
		Charge/Discharge current is less than 50 mA	





## REVISION HISTORY

REVISION	DATE	CHANGE NOTIFICATION	DESCRIPTION
Version I	Oct, 2, 2019	-	- Add X8G product range, 0805, InF to 10nF, 50V to 100V
Version 0	Dec. 12, 2018	-	- New





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